

**Search Notes**

Application/Control No.

10/521,594

Examiner

EDMUND H. LEE

Applicant(s)/Patent under  
Reexamination

IWASAKI ET AL.

Art Unit

1791

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
<b>425</b>	<b>388</b>	6/22/2009	<b>EHL</b>
264/549,550,572,554		6/22/2009	EHL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
264/549,550,572,553	6/22/2009	EHL
425/388	6/22/2009	EHL
UPDATED	6/22/2009	EHL